## Industrial Embedded Systems - Design for Harsh Environment -

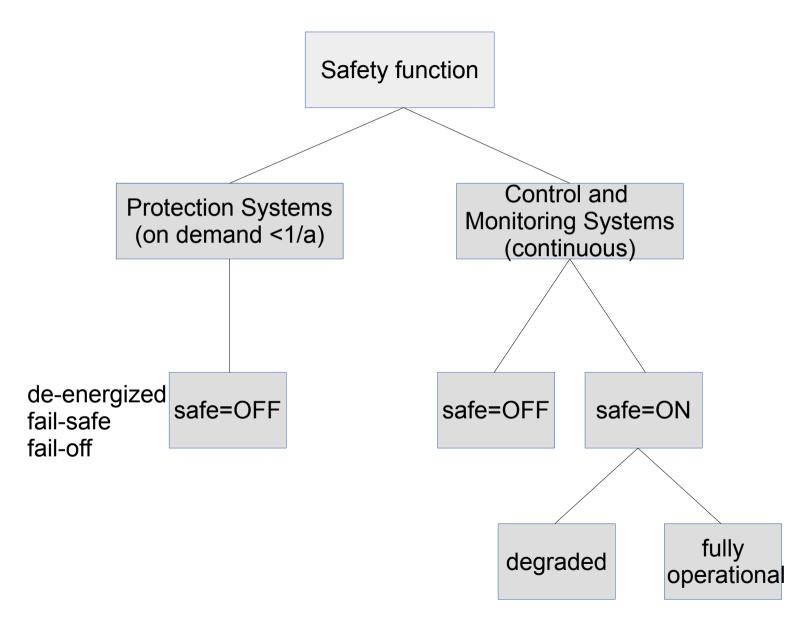
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IN2244

Part VI – Safety Architectures WS 2014/15

Technische Universität München

## Fail-safe and Fail-operational Systems



## **Architecture Constraints**

Safe failure fraction	Hardware fault tolerance (see note 2)		
	0	1	2
< 60 %	Not allowed	SIL1	SIL2
60 % – < 90 %	SIL1	SIL2	SIL3
90 % – < 99 %	SIL2	SIL3	SIL4
≥ 99 %	SIL3	SIL4	SIL4

NOTE 1 See 7.4.3.1.1 to 7.4.3.1.4 for details on interpreting this table.

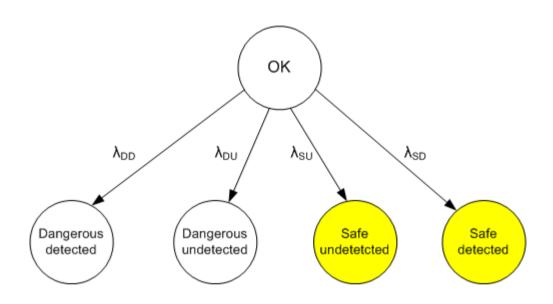
NOTE 2 A hardware fault tolerance of N means that N + 1 faults could cause a loss of the safety function.

NOTE 3 See annex C for details of how to calculate safe failure fraction.

Source: IEC61508

- Besides providing a specific quality (failure rate) a safety function must be hosted by a specific architecture in context of IEC 61508
- Besides architecture constraints also specific fault detection mechanisms must be realized by the final design. This is expressed by the safe failure fraction (SFF)

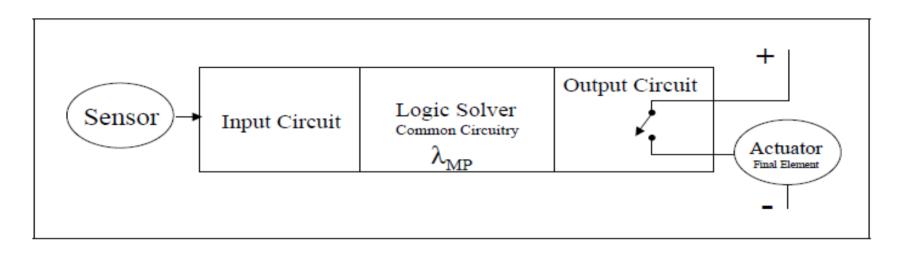
## **Safe Failure Fraction (SFF)**

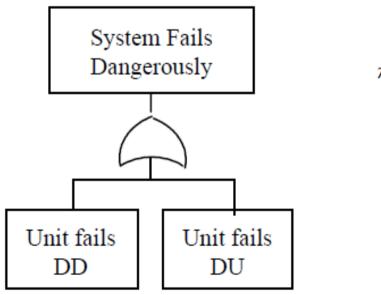


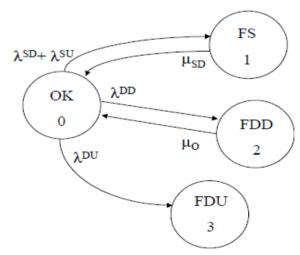
 Failure (this is the same failure rate as in the reliability lecture) can happen in a safe or dangerous way. Detection mechanisms are software enabled in the context of complex systems (involving microcomputers).

• 
$$SFF = 1 - \frac{\lambda_{du}}{\lambda_{total}}$$
;  $\lambda_{total} = \lambda_{du} + \lambda_{dd} \lambda_{su} + \lambda_{sd}$ 

## 1001 System



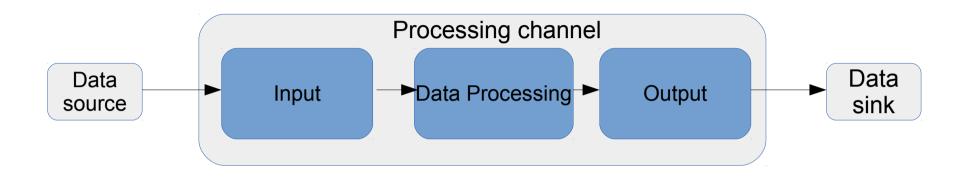




#### Source:

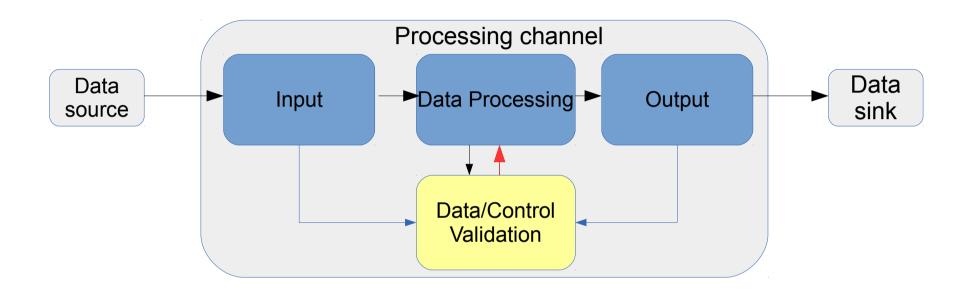
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## 1001 Software



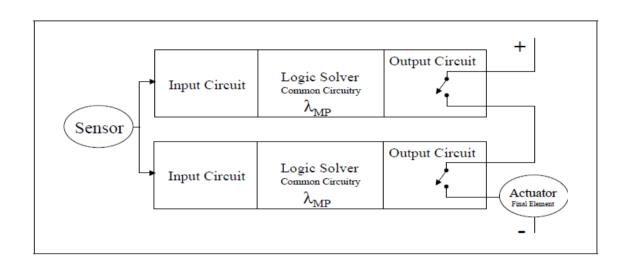
- Reliability (random faults): see previous calculations
- Reliability (systematic faults): highly affected
- Safety: 1oo1 architecture, not used

## 1001 Software

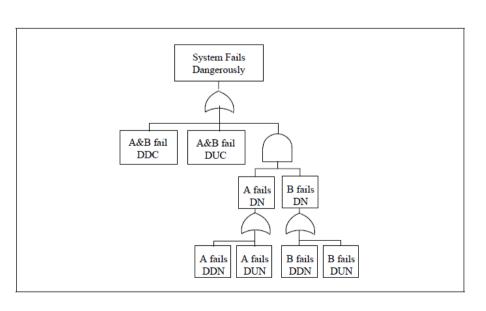


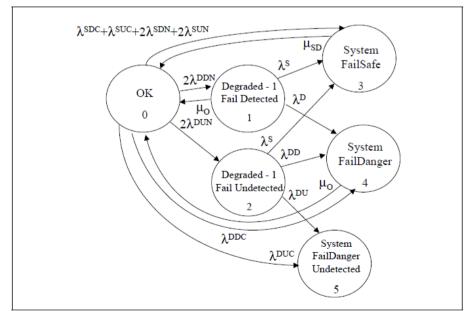
- Still 1001.
- Provides some data and control flow checks (self-monitoring)
  - Internal watchdog, acceptance tests
- Use: not used in safety-related applications, reliability increase (depends on application)

## 1002 System



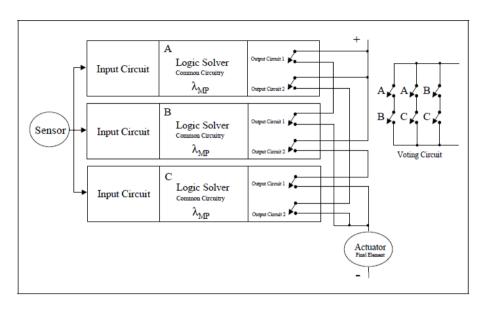
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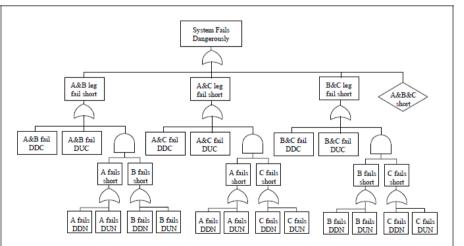


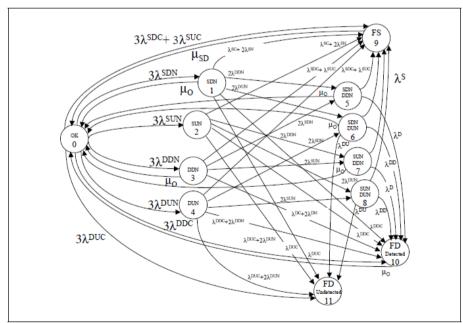


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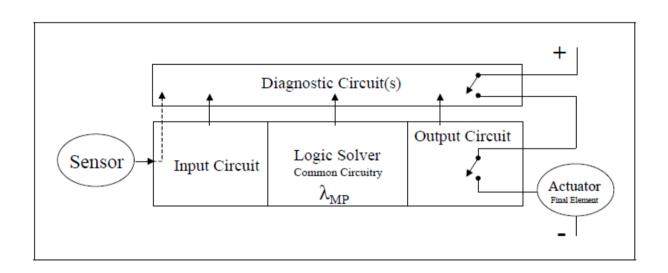
## 2003 System

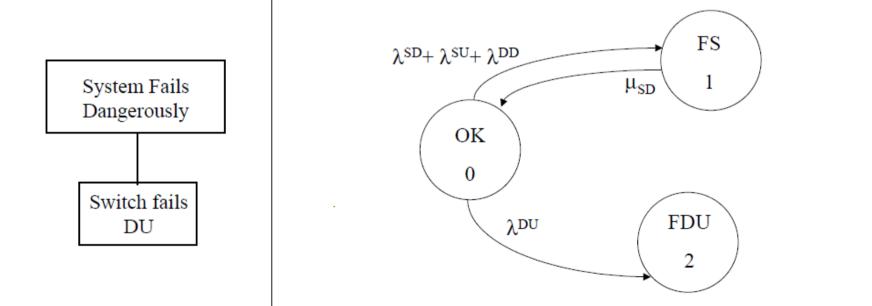




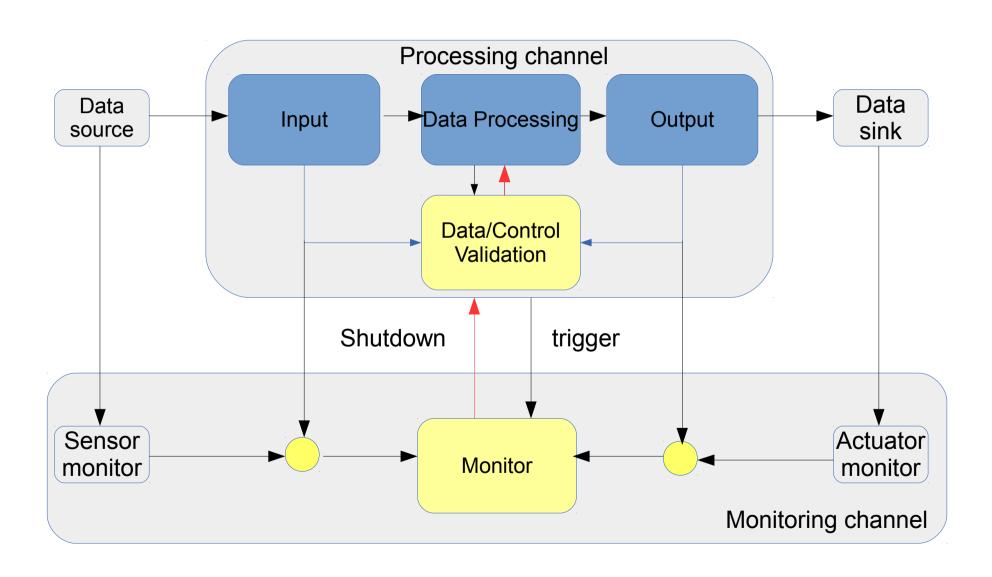


## 1001D System

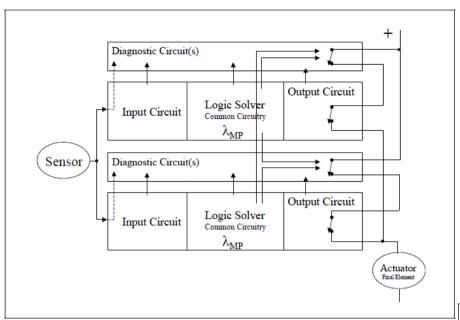




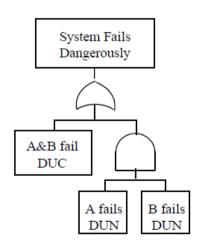
## **External Diagnostics (MooND Architectures)**

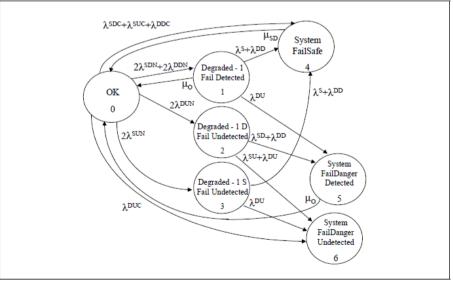


## 1002D System

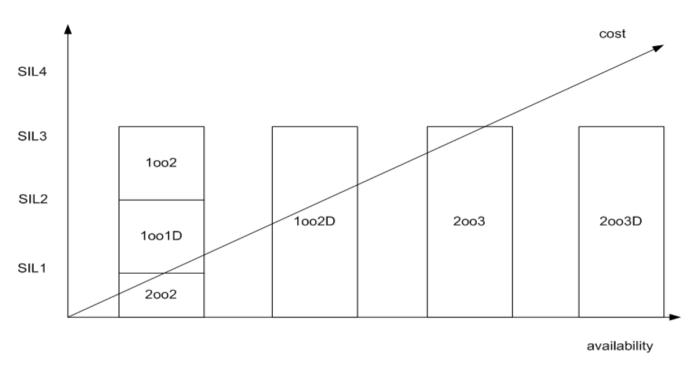


#### Source:





## **Architectures and Cost**



Source:

Architecture	Number of units	Output Switches	Objective
1001	1	1	Base unit
1002	2	2	High Safety
2002	2	2	Maintain output
1001D	1	2	High Safety
2003	3	6	Safety and Availability
2002D	2	4	Safety and Availability
1002D	2	4	Safety and Availability – biased toward Safety

## **Systematic Failures**

- Architecture: common cause failures, dependency failures
  - Freedom from interference
  - Look at common cause failures in previous Markov diagrams
- Software: SIL for software renamed to systematic capability (SC) in IEC61508 Edition 2.0
  - SC N supports a safety function of SIL N